



THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Wallace T.Y. Tang

Art Unit : 1763

Serial No.: 09/134,147

Examiner: Sylvia R. MacArthur

Filed

: August 14, 1998

Title

: IN-SITU REAL-TIME MONITORING TECHNIQUE AND APPARATUS FOR

DETECTION OF THIN FILMS DURING CHEMICAL/MECHANICAL

POLISHING PLANARIZATION

MAIL STOP AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

11/12/04 Date:

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Sheet	1	of	1

Substitute Form PTO-144 U.S (Modified)

partment of Commerce ont and Trademark Office

Attorney's Docket No. 05542-459003

Application No. 09/134,147

Information Disclosure Statement by Applicant (Use several sheets if necessary)

NOV 1 7 2004

Applicant Wallace T.Y. Tang

Filing Date

Group Art Unit 1763

(37 CFR §1.98(b))

August 14, 1998

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
·	AG						
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	AI						
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	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or	T		Translation	on
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL	KR 92-20600	11/1992	KR			Partial Translation	
	AM	JP 60-79304	05/1985	JP			Partial Translation	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)					
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with					
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